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FORM PTO-1449
(REV. 7-80)

U.S. DEPARTMENT OF COMMERCE
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ATTY. DOCKET NO.
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SERIAL NO.

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APPLICANT
Y. TAKEZAWA et al
FILING DATE
February 26, 2002

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	DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES <input type="checkbox"/> NO <input type="checkbox"/>
DM	AL 11-330185	11/30/99	Japan (w/ English Abstract)			<input type="checkbox"/> <input type="checkbox"/>
	AM 2000-131243	05/12/00	Japan (w/ English Abstract)			<input type="checkbox"/> <input type="checkbox"/>
	AN 11-235097	08/27/99	Japan (w/ English Abstract)			<input type="checkbox"/> <input type="checkbox"/>
	AO 9-222393	08/26/97	Japan (w/ English Abstract)			<input type="checkbox"/> <input type="checkbox"/>
	AP 10-115601	05/06/98	Japan (w/ English Abstract)			<input type="checkbox"/> <input type="checkbox"/>

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

DM	AR	T. Ikeda et al, "Development of the Ultrasonic Degradation Tester for Low Voltage Cables", TRANSACTIONS OF THE INSTITUTE OF ELECTRICAL ENGINEERS OF JAPAN, Vol. 120-B, No. 11, pp. 1437-1442, 2000.
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DM	AL 11-118773	04/30/99	Japan (w/ English Abstract)			<input type="checkbox"/>	<input type="checkbox"/>
	AM 10-19856	01/23/98	Japan (w/ English Abstract)			<input type="checkbox"/>	<input type="checkbox"/>
	AN 7-35732	02/07/95	Japan (w/ English Abstract)			<input type="checkbox"/>	<input type="checkbox"/>
	AO 7-245869	09/19/95	Japan (w/ English Abstract)			<input type="checkbox"/>	<input type="checkbox"/>
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